

**Notice of References Cited**

Application/Control No.

10/532,440

Applicant(s)/Patent Under  
Reexamination  
INOUE ET AL.

Examiner

Stephen J. Ralis

Art Unit

3742

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0017057	01-2005	Motomi et al.	228/212
*	B	US-5,044,541	09-1991	Sekine et al.	228/6.1
*	C	US-4,162,387	07-1979	De Candia, Ettore	219/79
*	D	US-4,928,383	05-1990	Kaczmarek et al.	29/711
*	E	US-4,628,722	12-1986	Mauer et al.	29/812.5
*	F	US-4,670,961	06-1987	Fontaine et al.	29/429
*	G	US-6,595,407	07-2003	McNamara et al.	228/212
*	H	US-4,946,089	08-1990	Baulier et al.	228/45
*	I	US-6,100,497	08-2000	Maruyama et al.	219/121.63
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 02144267 A	06-1990	Japan	SHIMOYAMA et al.	
	O	WO 03/039941 A1	05-2003	WORLD INTELLECT	MOTOMI et al.	
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

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